

What is claimed is:

1. A method of verifying a mask for a mask ROM,
comprising the steps of:

5 selecting a first and second chips manufactured by
 a process with said mask;
 implanting a random code into said first chip and
 testing said first chip for generating a first test
 result;
10 implanting a reverse tone code derived from said
 random code into said second chip and testing
 said second chip for generating a second test
 result; and
 comparing said first and second test results for
15 determining if said mask is defective.

2. A method according to claim 1, wherein said
first and second chips are selected from two wafers,
respectively.

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3. A method according to claim 1, wherein said
first and second chips are selected from two die regions on a
wafer.

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4. A method of verifying a mask for a mask ROM,

comprising the steps of:

5 selecting a plurality of chips manufactured by a
 process with said mask;
 implanting a plurality of codes exclusive to each
 other into said plurality of chips, respectively;
 testing said plurality of chips for generating a
 plurality of test results; and
 comparing said plurality of test results for
 determining if said mask is defective.

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5. A method according to claim 4, wherein said plurality of chips are selected from individual wafers, respectively.

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6. A method according to claim 4, wherein said plurality of chips are selected from individual die regions on a wafer.